

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Appl. No.	10/549,865	Confirmation No.	4772
First Inventor	Victor Higgs	Filing Date	July 28, 2006
TC/AU	2886	Examiner	Isiaka O. Akanbi
Title:	Detection Method and Appartus Metal Particulates on Semiconductors		
Docket No.:	NAN165 US (8037)	Customer No.:	34036

Saratoga, California
August 3, 2009

Mail Stop ISSUE FEE
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P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER NOTICE OF ALLOWANCE**UNDER 37 C.F.R. 1.312**

Dear Sir:

In response to Notice of Allowance dated May 4, 2009, please amend the above-identified application as follows.

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.